



DEPARTMENT OF
ENERGY, MINES AND RESOURCES
MINES BRANCH



*COMPUTER PROGRAMS FOR X-RAY
CRYSTALLOGRAPHY
PART II:
PROGRAM FOR DIFFRACTOMETER
ANGLE SETTINGS*

E. J. GABE

MINERAL SCIENCES DIVISION

JULY 1967



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COMPUTER PROGRAMS FOR X-RAY CRYSTALLOGRAPHY.

PART II:

PROGRAM FOR DIFFRACTOMETER ANGLE SETTINGS

by

F. J. Gabe*

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ABSTRACT

This program calculates the three setting angles for a 4-circle diffractometer in the bisecting position ($\omega = 0$). It is applicable to any system, and any type of systematic absence may be allowed for. The required angles may be calculated for any segment of reciprocal space.

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Direction des mines

Rapport de recherches R 191

PROGRAMMES D'ORDINATEUR

POUR LA RADIOCRISTALLOGRAPHIE

PARTIE II:

PROGRAMME POUR CALCULER LES ANGLES

DE RÉGLAGE D'UN DIFFRACTOMÈTRE

par

E. J. Gabe*

- - -
RÉSUMÉ

Le présent programme calcule les trois angles de réglage pour un diffractomètre à 4 cercles en position bissectrice ($\omega = 0$). Il s'applique à tout système et l'on peut tenir compte de tout genre d'absence systématique. Les angles requis peuvent être calculés pour tout segment d'espace réciproque.

*Proposé à la recherche, Section de la minéralogie, Division des sciences minérales, Direction des mines, ministère de l'Energie, des Mines et des Ressources, Ottawa, Canada.

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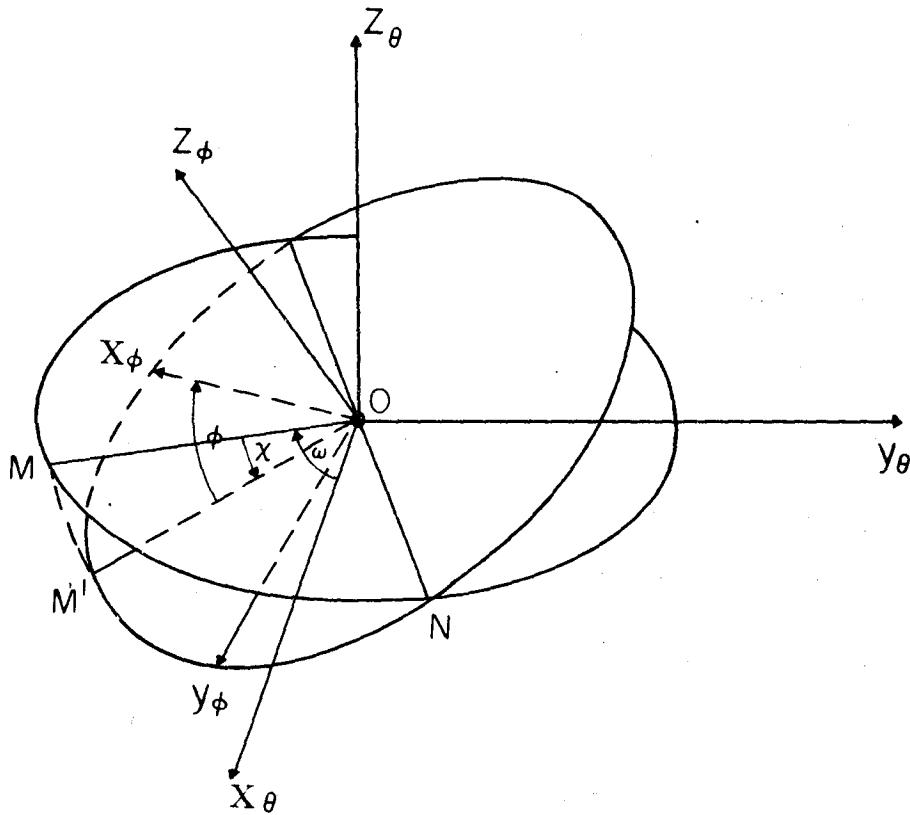
INTRODUCTION

This is the second program in the series of programs for X-ray crystallography. In order to use a 3- (or 4-) circle diffractometer for the collection of intensity data for structure analysis, it is necessary to calculate the setting angles ϕ , χ , (ω) and 2θ for every reflection h, k, ℓ within a sphere of radius $2 \sin \theta_{\max}$. This program calculates the required angles for the $\omega = 0$ case from orientation information about 3 reflections h_i, k_i, ℓ_i ($i = 1, 2, 3$). The orientation matrix R is calculated, as well as the real and reciprocal cell lengths and angles.

GENERAL DESCRIPTION

In essence, a 3- or 4-circle diffractometer is a device that will allow any reciprocal-space vector \tilde{h}_i to be turned into a position so that diffraction can occur in a horizontal plane, i.e., the vector bisects the angle between the incident and diffracted beams. In a 3-circle device, this can only be done in two ways, for which $\omega = 0$, but in a 4-circle device it may be done in an infinite number of ways. This allows the instrument to be set in a variety of ways, as well as permitting complete rotation about \tilde{h}_i .

The instrument is described in terms of the three Eulerian angles ω , χ , and ϕ . Reference to the illustration below will show how the Eulerian angles are chosen in this particular case:



If the θ -axial system is chosen so that Z_θ is parallel to the θ -axis of the instrument and Y_θ bisects the angle 2θ , then X_θ will be in the direction of the diffraction-vector. The other system is chosen so that Z_ϕ is along the ϕ -axis of the instrument and X_ϕ is at $\phi = 0$. Any vector x_ϕ, y_ϕ, z_ϕ may be brought into coincidence with the X_θ -axis by suitable changes to the angles ω, ϕ , and χ . To obtain the angles, consider a unit vector along X_θ :

The projection of x_θ onto OM = $\cos\omega$

and x_θ onto ON = $\sin\omega$.

The projection of OM onto OM' = $\cos\omega\cos\chi$,

and OM' onto X_ϕ = $\cos\omega\cos\chi\cos\phi$.

The projection of ON onto $X_\phi = -\sin\omega\sin\phi$;

thus, the projection of x_θ onto $X_\phi = \cos\omega\cos\chi\cos\phi - \sin\omega\sin\phi$.

Similarly,

the projection of OM onto $Y_\phi = \cos\omega\cos\chi\sin\phi$,

the projection of ON onto $Y_\phi = \sin\omega\cos\phi$;

thus the projection of x_θ onto $Y_\phi = \cos\omega\cos\chi\sin\phi + \sin\omega\cos\phi$.

Also,

the projection of OM onto $Z_\phi = \cos\omega\sin\chi$.

Hence, any vector in the direction X_θ is made up of components

$$\begin{aligned} & \cos\omega\cos\chi\cos\phi - \sin\omega\sin\phi \\ & \cos\omega\cos\chi\sin\phi + \sin\omega\cos\phi \\ & \cos\omega\sin\chi \end{aligned} \quad \left. \right\} \quad (1)$$

in the ϕ -axis system.

Any vector in the crystal system (h, k, l) may be described in terms of orthogonal components x_o, y_o, z_o if we define an orthogonality matrix T_{ij} such that

$$\begin{pmatrix} x_o \\ y_o \\ z_o \end{pmatrix} = \begin{pmatrix} T_{ij} \end{pmatrix} \begin{pmatrix} h \\ k \\ l \end{pmatrix},$$

where

$$T_{ij} = \begin{bmatrix} a^* & b^*\cos\gamma^* & c^*\cos\beta^* \\ 0 & b^*\sin\gamma^* & -c^*\sin\beta^*\cos\alpha \\ 0 & 0 & 1/c \end{bmatrix}$$

and x_o lies along a^* , y_o is in the a^*b^* plane and z_o is perpendicular to that plane.

There must also exist a rotation matrix R which will rotate the orthogonal system into coincidence with the ϕ -system, and we already know that if 3 angles ω, χ and ϕ are chosen so that the components of the vector in the ϕ -system satisfy (1), changes ω, χ, ϕ in the appropriate settings will bring the vector into the diffracting position, i.e. it will lie along x_ϕ . Thus,

$$\frac{Z \sin \theta}{\lambda} \begin{pmatrix} \cos \omega \cos \chi \cos \phi - \sin \omega \sin \phi \\ \cos \omega \cos \phi \sin \phi + \sin \omega \cos \phi \\ \cos \omega \sin \chi \end{pmatrix} = \underset{\sim}{R} \cdot \underset{\sim}{T} \cdot \begin{pmatrix} h \\ k \\ l \end{pmatrix}, \quad (2)$$

where $Z \sin \theta / \lambda$ is the magnitude of the vector. If we have 3 non-coplanar reflections, h_i, k_i, l_i , which define a right-handed coordinate system, we may write:

$$\underset{\sim}{\Theta} = \underset{\sim}{R} \cdot \underset{\sim}{T} \cdot \underset{\sim}{H},$$

where $\underset{\sim}{H}$ is the matrix of h, k, l values and $\underset{\sim}{\Theta}$ is the matrix of angular components $\omega_i, \phi_i, \chi_i, \theta_i$. Thus,

$$\underset{\sim}{\Theta} \underset{\sim}{H}^{-1} = \underset{\sim}{R} \cdot \underset{\sim}{T}.$$

Knowing $\underset{\sim}{T}$, it is possible to calculate $\underset{\sim}{R}$ but, in fact, this is not necessary.

In the case of the 3-circle instrument, i.e. $\omega = 0$, for any reflection h, k, l ,

(2) becomes:

$$\underset{\sim}{R} \cdot \underset{\sim}{T} \cdot \begin{pmatrix} h \\ k \\ l \end{pmatrix} = \begin{pmatrix} Z \sin \theta / \lambda \cos \chi \cos \phi \\ Z \sin \theta / \lambda \cos \chi \sin \phi \\ Z \sin \theta / \lambda \sin \chi \end{pmatrix} = \begin{pmatrix} x_\phi \\ y_\phi \\ z_\phi \end{pmatrix}.$$

Hence, as we know the matrix $\underset{\sim}{R} \cdot \underset{\sim}{T}$,

$$\begin{aligned} \phi &= \tan^{-1} \left(\frac{y_\phi}{x_\phi} \right) \\ \chi &= \tan^{-1} \left(\frac{z_\phi}{\sqrt{x_\phi^2 + y_\phi^2}} \right) \\ 2\theta &= 2 \tan^{-1} \left(\frac{\sqrt{(x_\phi^2 + y_\phi^2 + z_\phi^2) / (4 - x_\phi^2 - y_\phi^2 - z_\phi^2)}}{x_\phi^2 + y_\phi^2 + z_\phi^2} \right). \end{aligned}$$

The 4-circle case is more easily treated with matrices. If we have a vector x_ϕ, y_ϕ, z_ϕ in the ϕ -system, it can be transformed to the Θ -system by applying a series of rotations Φ, X, Ω ,

where

$$\begin{aligned}\tilde{\Phi} &= \begin{bmatrix} \cos \phi & \sin \phi & 0 \\ -\sin \phi & \cos \phi & 0 \\ 0 & 0 & 1 \end{bmatrix}, \\ \tilde{X} &= \begin{bmatrix} \cos \chi & 0 & \sin \chi \\ 0 & 1 & 0 \\ -\sin \chi & 0 & \cos \chi \end{bmatrix}, \\ \tilde{\Omega} &= \begin{bmatrix} \cos \omega & \sin \omega & 0 \\ -\sin \omega & \cos \omega & 0 \\ 0 & 0 & 1 \end{bmatrix},\end{aligned}$$

such that

$$\tilde{\Omega} \cdot \tilde{X} \cdot \tilde{\Phi} \cdot \begin{pmatrix} x_\phi \\ y_\phi \\ z_\phi \end{pmatrix} = \tilde{\Omega} \begin{pmatrix} x_\phi \\ y_\phi \\ z_\phi \end{pmatrix} = \begin{pmatrix} x_\theta \\ y_\theta \\ z_\theta \end{pmatrix}$$

if the Θ vector is in the diffracting position.

Hence,

$$\tilde{\Omega} \cdot \tilde{X} \cdot \tilde{\Phi} \cdot \tilde{R} \cdot \tilde{T} \begin{pmatrix} h \\ k \\ l \end{pmatrix} = \begin{pmatrix} x_\theta \\ y_\theta \\ z_\theta \end{pmatrix}$$

is the full equation for any reflection h, k, l to diffract.

Expanding $\tilde{\Omega} \cdot \tilde{X} \cdot \tilde{\Phi}$ gives $\tilde{Q} =$

$$\begin{bmatrix} \cos \omega \cos \chi \cos \phi - \sin \omega \sin \phi & \cos \omega \cos \chi \sin \phi + \sin \omega \cos \phi & \cos \omega \sin \chi \\ -\sin \omega \cos \chi \cos \phi - \cos \omega \sin \phi & -\sin \omega \cos \chi \sin \phi + \cos \omega \cos \phi & -\sin \omega \sin \chi \\ -\sin \chi \cos \phi & -\sin \chi \sin \phi & \cos \chi \end{bmatrix}.$$

From the expressions (1) we may find ϕ and χ for any value of ω we choose, and then form the matrix \tilde{Q} . It is more convenient, however, to consider only special cases ($\omega = 0$ or $\chi = 90^\circ$) where considerable simplification results. In any case, it is not particularly meaningful to find the settings χ and ϕ for arbitrary values of ω .

A more useful treatment is to consider rotation around the diffraction vector by the azimuthal angle ψ , for which the matrix \tilde{Q} becomes:

$$\tilde{P} \cdot \tilde{Q} = \begin{bmatrix} 1 & 0 & 0 \\ 0 & \cos \psi & \sin \psi \\ 0 & -\sin \psi & \cos \psi \end{bmatrix} \cdot \tilde{Q},$$

which still has the form of \tilde{Q} and from which new values of ω , ϕ and χ may be extracted for any value of ψ :

$$\chi = \tan^{-1} (\sqrt{Q_{31}^2 + Q_{32}^2} / Q_{33})$$

$$\phi = \tan^{-1} (Q_{32} / Q_{31})$$

$$\omega = \tan^{-1} (-Q_{23} / Q_{13})$$

If the starting position ($\psi = 0$) is arbitrarily chosen as $\omega = 0$, we have:

$$\begin{aligned} Q &= P \begin{bmatrix} \cos \chi \cos \phi & \cos \chi \sin \phi & \sin \chi \\ -\sin \phi & \cos \phi & 0 \\ -\sin \chi \cos \phi & -\sin \chi \sin \phi & \cos \chi \end{bmatrix} \\ &= \begin{bmatrix} \cos \chi \cos \phi & \cos \chi \sin \phi & \sin \chi \\ -\cos \psi \sin \phi - \sin \psi \sin \chi \cos \phi & \cos \psi \cos \phi - \sin \psi \sin \chi \sin \phi & \sin \psi \cos \chi \\ \sin \psi \sin \phi - \cos \psi \sin \chi \cos \phi & -\sin \psi \cos \phi - \cos \psi \sin \chi \sin \phi & \cos \psi \cos \chi \end{bmatrix}, \end{aligned}$$

from which the values of ω , χ and ϕ may be extracted.

To return to the case of the 3 setting reflections, a useful by-product of the matrix $\tilde{R} \cdot \tilde{T}$ is the metric tensor G^{-1} . This may be formed as follows:

$$\begin{aligned} \tilde{G}^{-1} &= \tilde{R} \cdot \tilde{T} \cdot \tilde{R} \cdot \tilde{T} \\ &= \tilde{T} \cdot \tilde{R} \cdot \tilde{R} \cdot \tilde{T} = \tilde{T} \cdot \tilde{\tilde{R}} \end{aligned}$$

because \tilde{R} is orthogonal. Then

$$\tilde{G}_{ij}^{-1} = a_i^* a_j^* \cos \alpha_{ij}^*,$$

from which the reciprocal cell parameters may be found. In similar manner the direct cell parameters may be found from G .

The separate problem of indexing through any segment of reciprocal space with any order of changes to h , k , and ℓ , has been solved as follows:

Any reflection $hk\ell$ (referred to hereafter as h) may be reached from an origin reflection h_0 by an integral number of steps Δh in the 3 directions; i.e.

$$h = h_0 + n_1 \Delta h_1 + n_2 \Delta h_2 + n_3 \Delta h_3,$$

$$\text{i.e. } \begin{pmatrix} h \\ k \\ \ell \end{pmatrix} = \begin{pmatrix} h_0 \\ k_0 \\ \ell_0 \end{pmatrix} + \begin{bmatrix} \Delta h_1 & \Delta h_2 & \Delta h_3 \\ \Delta k_1 & \Delta k_2 & \Delta k_3 \\ \Delta \ell_1 & \Delta \ell_2 & \Delta \ell_3 \end{bmatrix} \begin{pmatrix} n_1 \\ n_2 \\ n_3 \end{pmatrix},$$

$$\text{or } (h_i) = (h_{oi}) + [\Delta h_{ij}] (n_j).$$

The steps Δh_{i1} , Δh_{i2} and Δh_{i3} are chosen so that they are increments in going from one layer to the next, one line to the next, and one point to the next, in reciprocal space.

If we wish to have layers normal to h , lines parallel to k , and successive points along ℓ ,

$$[\Delta h_{ij}] = \begin{bmatrix} 1 & 0 & 0 \\ 0 & 1 & 0 \\ 0 & 0 & 1 \end{bmatrix}.$$

Thus, the 3 steps Δh represent the 3 directions formed by the intersections of the 3 planes bounding the required volume of reciprocal space. It is easy to see how this can be adapted to cover the limited regions required in the higher-symmetry systems. It may be necessary, or more convenient, to scan the required volume of reciprocal space in more than one segment but at the same time avoid duplicating reflections already considered or symmetrically equivalent reflections. This is achieved by allowing a different choice of origin reflection for each segment.

In order to proceed from line to line and layer to layer correctly, it is necessary to know the starting reflection for each line and layer. This is worked out at the beginning of each segment, by specifying a starting reflection h_s and then working out the first line and first layer reflections as follows:

$$(h_{si}) = (h_{oi}) + [\Delta h_{ij}] (n_j);$$

therefore $[\Delta h_{ij}]^{-1} (h_{si} - h_{oi}) = (n_j).$ (3)

From which the first reflection of the layer (subscript L) is:

$$h_{Li} = h_{oi} + [\Delta h_{il}] n_1,$$

the first reflection of the line (subscript ℓ) is:

$$h_{\ell i} = h_{Li} + [\Delta h_{i\ell}] n_2,$$
 (4)

and the first point (subscript s) is:

$$h_{si} = h_{\ell i} + [\Delta h_{i3}] n_3.$$

An example will clarify the procedure. Suppose we wish to find all the reflections with h negative for a monoclinic crystal, starting at the reflection $-3, 2, 4$ and indexing so that k changes fastest, h next and ℓ least.

$$\Delta h_{ij} = \begin{bmatrix} 0 & -1 & 0 \\ 0 & 0 & 1 \\ 1 & 0 & 0 \end{bmatrix} \text{ and } [\Delta h_{ij}]^{-1} = \begin{bmatrix} 0 & 0 & 1 \\ -1 & 0 & 0 \\ 0 & 1 & 0 \end{bmatrix}.$$

h^{0i} is $-1, 0, 1$ as we are considering a monoclinic crystal and we do not wish to repeat reflections with $h = 0$ or $\ell = 0$. Thus, from (3):

$$[\Delta h_{ij}]^{-1} \begin{pmatrix} -3 & -1 \\ 2 & 0 \\ 4 & 1 \end{pmatrix} = \begin{pmatrix} 0 & 0 & 1 \\ -1 & 0 & 0 \\ 0 & 1 & 0 \end{pmatrix} \begin{pmatrix} 2 \\ 2 \\ 3 \end{pmatrix} = \begin{pmatrix} 3 \\ 2 \\ 2 \end{pmatrix} = (n_j),$$

and from (4):

$$\left. \begin{array}{l} h_L = -1 + 0 = -1 \\ k_L = 0 + 0 = 0 \\ \ell_L = 1 + 3 = 4 \end{array} \right\} \text{Start of layer,}$$

$$\left. \begin{array}{l} h_\ell = -2 + -1 = -3 \\ k_\ell = 0 + 0 = 0 \\ \ell_\ell = 0 + 4 = 4 \end{array} \right\} \text{Start of line within layer,}$$

$$\left. \begin{array}{l} h_s = 0 + -3 = -3 \\ k_s = 2 + 0 = 2 \\ \ell_s = 0 + 4 = 4 \end{array} \right\} \text{Starting or current reflection.}$$

After each reflection the current values are incremented until a limit is exceeded. The line reflection is then incremented and the current reflection set equal to it, until a limit is exceeded. The layer reflection is then incremented and the line and current reflections set equal to it until a limit is exceeded.

DETAILS OF THE CALCULATION

h, k, l, ϕ, x, θ values are read for 3 reflections which define a right-handed coordinate system. From the details of these reflections the matrix $\underline{\underline{R}} \cdot \underline{\underline{T}}$ is computed and, from this, G^{-1} and G , which give the reciprocal and real cell parameters. Further information concerning the segments of reciprocal space required and the order of indexing is read together with systematic absence information. Each reflection h, k, l is tested against an expression of the type:

$$Ah + Bk + Cl = Dm + E,$$

where A, B, C, D, and E determine if the reflection is acceptable. Any number of these conditions may be applied to axial, zonal or general reflections.

From the details of the starting and origin reflections given, n_1 , n_2 and n_3 are calculated, and then reflections are generated in the preset sequence until all reflections in the reciprocal segment with 2θ values less than some limit have been dealt with. The same operations are then repeated for any other segments required.

Input:

The details of the description of both input and output are the same as for the first program in this series. The input is all from punched cards and the output is all on the lineprinter.

<u>Card Column (c.c.)</u>	<u>Contents</u>	<u>Comments</u>
<u>First Card</u>		
1-3	xxx	No. of structures to be processed
4-80	blanks	

The remainder of the cards are in sets, 1 set per structure.

Title Card

1-70	Title of structure
71-80	blanks

Wavelength Card

1-8	xx.xxxxx	Wavelength of radiation used
9-80	blanks	

Reflection Cards

There are three of these cards.

1-4	xxx b	h
5-8	xxx b	k
9-12	xxx b	l
13-21	xxx.xxxx b	ϕ
22-30	xxx.xxxx b	x
31-39	xxx.xxxx b	θ
40-80	blanks	

} Values for reflection h, k, l

Limits Card

1-4	xxx b	No. of reciprocal space segments (N)
5-10	xxx.xx	Maximum value of 2θ
11-80	blanks	

Reflection Condition Cards

1-3	xxx	No. of reflection conditions (R)
4-80	blanks	

This is followed by R cards

1-5	xxx bb	Type of reflection to which condition applies; see below
6-10	xxx bb	A
11-15	xxx bb	B
16-20	xxx bb	C
21-25	xxx bb	D
26-30	xxx bb	E
31-80	blanks	

The first number has the value 1-7 as follows:

1	00 ℓ	reflections only
2	0k0	" "
3	h00	" "
4	0k ℓ	" "
5	h0 ℓ	" "
6	hk0	" "
7	hk ℓ	" "

e.g., parameters 7 1 1 1 2 0 would mean that for all reflections h, k, ℓ ,

$$Ah + Bk + C\ell = Dn + E$$

would be

$$h + k + \ell = 2n$$

for the reflection to be present.

Any number R of these cards may be given, and multiple conditions may be given for the same reflection type.

Segment Cards

The reflection condition cards are followed by N-cards, each of which deals with the indexing of 1 segment of reciprocal space.

1-4	xxx b	h_o	
5-8	xxx b	k_o	
9-12	xxx b	ℓ_o	
13-16	xxx b	h_{11}	
17-20	xxx b	h_{21}	Origin-defining reflection
21-24	xxx b	h_{31}	
25-28	xxx b	h_{12}	Increment steps in $h k \ell$ for layers
29-32	xxx b	h_{22}	
33-36	xxx b	h_{32}	Increment steps in $h k \ell$ for lines
37-40	xxx b	h_{13}	
41-44	xxx b	h_{23}	Increment steps in $h k \ell$ for points
45-48	xxx b	h_{33}	
49-52	xxx b	h_s	
53-56	xxx b	k_s	Starting reflection
57-60	xxx b	ℓ_s	
61-80	blanks		

Output:

The first page of output gives the matrix $\tilde{R} \cdot \tilde{T}$ from which all calculations are done, the reciprocal and real lattice parameters, and the maximum values of h, k, ℓ . The subsequent pages list $h, k, \ell, \phi, x, 2\theta$ and L_p^{-1} for all reflections. All output quantities are labelled and no explanation is needed.

This whole sequence is repeated as many times as there are structures to be processed.

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Frank Ayres Jr. Theory and Problems of Matrices. Schaum Publishing Co., New York (1962).

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EJG:(PES) vb

PROGRAM LISTING

FORTRAN IV G LEVEL 2, MOD 0

MAIN

C PROGRAM TO CALCULATE SETTING ANGLES PHI,CHI AND TWO THETA FOR ALL PERMISSIBLE
C REFLECTIONS FOR ANY SYSTEM. GIVEN H,K,L,PHI,CHI AND THETA FOR ANY THREE
C NON-COPLANAR REFLECTIONS WHICH DEFINE A RIGHT HANDED SYSTEM

DIMENSION H(3),K(3),L(3),PHA(3),CHA(3),THATE(3),V(3,3),STHETA(3),
1CPHI(3),SPHI(3),CCHI(3),SCHI(3),TRG(3,3),VI(3,3),R(3,3),GI(3,3),
2A(3),ANG(3),G(3,3),AS(3),ANGS(3),FDH(3,3),FDHI(3,3),FSTHKL(3,3),
3VEC(3),VECVEC(3),DH(3,3),IND(3),RT(3,3),ICOND(10),HS(10),KS(10),
4LS(10),IR(10),IS(10),INDEX(3)
INTEGER H,DH,X,Y,Z,H0,HS,HMAX,FSTHKL
LNCD=1
LNPT=3
READ(LNCD,9)NSTRU
DO 1000 NSFTT=1,NSTRU
DEGREE=180.0/3.141593
RADIAN=1.0/DEGREE
3 WRITE(LNPT,3)
FORMAT(1H1,/)
READ(LNCD,13)
WRITE(LNPT,13)
13 FORMAT(7OH
1)
READ(LNCD,1)WAVE
1 FORMAT(F8.5)
DO 100 I=1,3
2 READ(LNCD,2)H(I),K(I),L(I),PHA(I),CHA(I),THATE(I)
FORMAT(3(I3,1X),3(F8.4,1X))
CPHI(I)=COS(PHA(I))*RADIAN
SPHI(I)=SIN(PHA(I))*RADIAN
CCHI(I)=COS(CHA(I))*RADIAN
SCHI(I)=SIN(CHA(I))*RADIAN
STHETA(I)=2.0/WAVE*SIN(THATE(I)*RADIAN)
V(3,I)=L(I)
V(2,I)=K(I)
100 V(1,I)=H(I)
C TRIIG MATRIX HPHI
DO 101 I=1,3
TRG(1,I)=STHETA(I)*CCHI(I)*CPHI(I)
TRG(2,I)=STHETA(I)*CCHI(I)*SPHI(I)
101 TRG(3,I)=STHETA(I)*SCHI(I)
C INVERT INDEX MATRIX
CALL INVERT(V,VI)
C COMPUTE UR MATRIX %RC AND PRINT
CALL MATMUL(TRG,VI,R)
4 FORMAT(10X,2HR%,I1,5H,1<# ,F12.8,4X,2HR%,I1,5H,2<# ,F12.8,4X,
12HR%,I1,5H,3<# ,F12.8)
DO 103 I=1,3
103 WRITE(LNPT,4)I,R(I,1),I,R(I,2),I,R(I,3)
C COMPUTE RECIPROCAL AND REAL METRIC TENSORS G-1 AND G

```
DO 104 I=1,3
DO 104 J=1,3
104 RT(J,I)=R(I,J)
CALL MATMUL (RT,R,GI)
CALL PARAM (GI,AS,ANGS)
WRITE(LNPT,5)AS(1),AS(2),AS(3),ANGS(1),ANGS(2),ANGS(3)
5 FORMAT(//5X,4HA*,F10.6,5X,4HB*,F10.6,5X,4HC*,F10.6,5X,
16HALF*,F10.5,5X,6HBET*,F10.5,5X,6HGAM*,F10.5)
CALL INVERT (GI,G)
CALL PARAM (G,A,ANG)
WRITE(LNPT,6)A(1),A(2),A(3),ANG(1),ANG(2),ANG(3)
6 FORMAT(//5X,4HA *,F10.6,5X,4HB *,F10.6,5X,4HC *,F10.6,5X,
16HALF *,F10.5,5X,6HBET *,F10.5,5X,6HGAM *,F10.5)
DO 105 I=1,3
DO 105 J=1,3
105 R(I,J)=R(I,J)*WAVE
C      ***** SETTINGS PROCEDURE *****
C READ NUMBER OF RECIPROCAL SEGMENTS ANGULAR LIMITS AND ABSENCE CODES
READ(LNCD,8)NUMSEG,THETA2
S=SIN(RADIAN*THETA2*0.5)
SS2=S+S
SS4=SS2*SS2
DO 200 J=1,3
ANG(J)=SIN(ANG(J)*RADIAN)
200 ANGS(J)=SIN(ANGS(J)*RADIAN)
HMAX=SS2/(AS(1)*ANGS(2)*ANG(3)*WAVE)+1.0
KMAX=SS2/(AS(2)*ANGS(3)*ANG(1)*WAVE)+1.0
LMAX=SS2/(AS(3)*ANGS(1)*ANG(2)*WAVE)+1.0
WRITE(LNPT,14)HMAX,KMAX,LMAX
14 FORMAT(//,3(6X,I3))
C READ REFLECTION CONDITIONS
READ(LNCD,9)NCOND
9 FORMAT(I3)
8 FORMAT(I3,1X,F6.2)
IF(NCOND.EQ.0) GO TO 208
DO 207 I=1,NCOND
207 READ(LNCD,10)ICOND(I),HS(I),KS(I),LS(I),IR(I),IS(I)
10 FORMAT(6(I3,2X))
208 DO 1000 NSEG=1,NUMSEG
READ(LNCD,7)HO,KO,LO,DH(1,1),DH(2,1),DH(3,1),DH(1,2),DH(2,2),
10 DH(3,2),DH(1,3),DH(2,3),DH(3,3),IND(1),IND(2),IND(3)
7 FORMAT(15(I3,1X))
DO 201 I=1,3
DO 201 J=1,3
201 FDH(I,J)=DH(I,J)
CALL INVERT (FDH,FDHI)
DO 202 I=1,3
INDEX(I)=FDHI(I,1)*(IND(1)-HO)+FDHI(I,2)*(IND(2)-KO)+FDHI(I,3)
```

```
1*(INDEX(3)-LO)
IF(INDEX(I).GE.0) GO TO 205
INDEX(I)=INDEX(I)-0.5
GO TO 202
205 INDEX(I)=INDEX(I)+0.5
CONTINUE
FSTHKL(1,1)=DH(1,1)*INDEX(1)+HO
FSTHKL(2,1)=DH(2,1)*INDEX(1)+KO
FSTHKL(3,1)=DH(3,1)*INDEX(1)+LO
DO 203 I=1,3
FSTHKL(I,2)=DH(I,2)*INDEX(2)+FSTHKL(I,1)
203 FSTHKL(I,3)=DH(I,3)*INDEX(3)+FSTHKL(I,2)
C START OF REFLECTION
NPAGE=55
301 X=FSTHKL(1,3)
Y=FSTHKL(2,3)
Z=FSTHKL(3,3)
C START A NEW PAGE AND PRINT HEADINGS
GO TO 503
302 NPAGE=0
WRITE(LNPT,11)
11 FORMAT(1H1,//20X,1HH,4X,1HK,4X,1HL,5X,7H PHI ,5X,7H CHI ,5X,7H
1 2THETA,5X,6H LP-1 ,/)
303 IF(X.EQ.0.AND.Y.EQ.0.AND.Z.EQ.0) GO TO 500
IF(NCOND.EQ.0) GO TO 304
DO 300 N=1,NCOND
JCOND=ICOND(N)
GO TO (310,320,330,340,350,360,370),JCOND
310 IF(X.EQ.0.AND.Y.EQ.0) GO TO 370
GO TO 300
320 IF(X.EQ.0.AND.Z.EQ.0) GO TO 370
GO TO 300
330 IF(Y.EQ.0.AND.Z.EQ.0) GO TO 370
GO TO 300
340 IF(X.EQ.0) GO TO 370
GO TO 300
350 IF(Y.EQ.0) GO TO 370
GO TO 300
360 IF(Z.EQ.0) GO TO 370
GO TO 300
370 LHS=IABS(X*HS(N)+Y*KS(N)+Z*LS(N))
M=TR(N)
IF(MOD(LHS,M).NE.IS(N)) GO TO 500
300 CONTINUE
C PHI,CHI AND 2THETA CALCULATION
304 SIGMA=0.0
DO 400 I=1,3
VEC(I)=R(I,1)*X+R(I,2)*Y+R(I,3)*Z
```

```
400 SIGMA=SIGMA+VEC(I)*VEC(I)
IF(SIGMA.GE.SS4) GO TO 500
BOT=ABS(VEC(1))
CEN=ABS(VEC(2))
TOP=ABS(VEC(3))
IF(BOT.NE.0.0) PHI=ATAN2(CEN,BOT)*DFGREE
IF(BOT.EQ.0.0) PHI=90.0
SIGMA=SIGMA-TOP*TOP
IF(SIGMA.NE.0.0) CHI=ATAN2(TOP,SQRT(SIGMA))*DEGREE
IF(SIGMA.EQ.0.0) CHI=90.0
CPHI AND CHI IN 270 TO 90 RANGE
IF(VEC(3).LT.0.0) CHI=360.0-CHI
IF(VEC(1).LT.0.0) GO TO 401
IF(VEC(2).LT.0.0) PHI=360.0-PHI
GO TO 402
401 IF(VEC(2).LT.0.0) PHI=180.0+PHI
IF(VEC(2).GE.0.0) PHI=180.0-PHI
402 IF(CHI.EQ.90.0.OR.CHI.EQ.270.0) PHI=999.0
SINSQ=0.25*(SIGMA+TOP*TOP)
THETA=2.0*DFGREE*ATAN1(SQRT(SINSQ/(1.0-SINSQ)))
TOP=4.0*SQRT(SINSQ*(1.0-SINSQ))
BOT=1.0-SINSQ-SINSQ
BOT=1.0+BOT*BOT
POL=TOP/BOT
WRITE(LNPT,12)X,Y,Z,PHI,CHI,THETA,POL
NPAGE=NPAGE+1
12 FORMAT(18X,I3,2X,I3,2X,I3,3(5X,F7.3),5X,F6.4)
C INCREMENT INDICES
500 X=X+DH(1,3)
Y=Y+DH(2,3)
Z=Z+DH(3,3)
IX=IABS(X)
IY=IABS(Y)
IZ=IABS(Z)
IF(IX.LT.HMAX.AND.IY.LT.KMAX.AND.IZ.LT.LMAX) GO TO 503
DO 501 I=1,3
FSTHKL(I,2)=FSTHKL(I,2)+DH(I,2)
501 FSTHKL(I,3)=FSTHKL(I,2)
IX=IABS(FSTHKL(1,3))
IY=IABS(FSTHKL(2,3))
IZ=IABS(FSTHKL(3,3))
IF(IX.LT.HMAX.AND.IY.LT.KMAX.AND.IZ.LT.LMAX) GO TO 301
DO 502 I=1,3
FSTHKL(I,1)=FSTHKL(I,1)+DH(I,1)
FSTHKL(I,2)=FSTHKL(I,1)
502 FSTHKL(I,3)=FSTHKL(I,2)
IX=IABS(FSTHKL(1,3))
IY=IABS(FSTHKL(2,3))
```

```
IZ=ABS(FSTHKL(3,3))
IF(IY.LT.HMAX.AND.IY.LT.KMAX.AND.IZ.LT.LMAX) GO TO 301
GO TO 1000
503 IF(NPAGE.GT.54) GO TO 302
GO TO 303
1000 CONTINUE
STOP
END
```

SUBROUTINES

```
C INVERT 3X3 MATRIX U TO GIVE UI
SUBROUTINE INVERT (U,UI)
DIMENSION U(3,3),UI(3,3)
UI(1,1)=U(2,2)*U(3,3)-U(2,3)*U(3,2)
UI(2,1)=-(U(2,1)*U(3,3)-U(2,3)*U(3,1))
UI(3,1)=U(2,1)*U(3,2)-U(2,2)*U(3,1)
UI(1,2)=-(U(1,2)*U(3,3)-U(1,3)*U(3,2))
UI(2,2)=U(1,1)*U(3,3)-U(1,3)*U(3,1)
UI(3,2)=-(U(1,1)*U(3,2)-U(1,2)*U(3,1))
UI(1,3)=U(1,2)*U(2,3)-U(1,3)*U(2,2)
UI(2,3)=-(U(1,1)*U(2,3)-U(1,2)*U(2,1))
UI(3,3)=U(1,1)*U(2,2)-U(1,2)*U(2,1)
DMAT=U(1,1)*UI(1,1)+U(1,2)*UI(2,1)+U(1,3)*UI(3,1)
DO 1000 I=1,3
DO 1000 J=1,3
1000 UI(I,J)=UI(I,J)/DMAT
RETURN
END
```

```
C MULTIPLY TWO MATRICES TOGETHER
SUBROUTINE MATMUL (AMAT,BMAT,CMAT)
DIMENSION AMAT(3,3),BMAT(3,3),CMAT(3,3)
DO 2000 I=1,3
DO 2000 J=1,3
CMAT(I,J)=0.0
DO 2000 K=1,3
2000 CMAT(I,J)=CMAT(I,J)+AMAT(I,K)*BMAT(K,J)
RETURN
END
```

```
C EXTRACT ELEMENTS FROM METRIC TENSOR
SUBROUTINE PARAM (W,D,T)
DIMENSION W(3,3),D(3),T(3)
DO 3000 I=1,3
J=I
3000 D(I)=SQRT(W(I,J))
T(1)=57.29578*ARCOS(W(2,3)/(D(2)*D(3)))
T(2)=57.29578*ARCOS(W(1,3)/(D(1)*D(3)))
T(3)=57.29578*ARCOS(W(1,2)/(D(1)*D(2)))
RETURN
END
```